

EMIPAK-2B PressFit Power Module Three Levels Half-Bridge Inverter Stage, 75 A



EMIPAK-2B
(package example)

FEATURES

- Trench IGBT technology
- FRED Pt® clamping diodes
- PressFit pins technology
- Exposed Al₂O₃ substrate with low thermal resistance
- Short circuit rated
- Square RBSOA
- Integrated thermistor
- Low internal inductances
- Low switching loss
- UL approved file E78996
- Material categorization: for definitions of compliance please see www.vishay.com/doc?99912



RoHS
COMPLIANT

PRODUCT SUMMARY

Q1 - Q4 IGBT STAGE	
V_{CES}	600 V
$V_{CE(ON)}$ typical at $I_C = 75$ A	1.7 V
I_C at $T_C = 89$ °C	75 A
Q2 - Q3 IGBT STAGE	
V_{CES}	600 V
$V_{CE(ON)}$ typical at $I_C = 75$ A	1.56 V
I_C at $T_C = 122$ °C	75 A
Speed	8 kHz to 30 kHz
Package	EMIPAK-2B
Circuit	3-levels half bridge inverter stage

DESCRIPTION

VS-ETF075Y60U is an integrated solution for a multi level inverter stage in a single package. The EMIPAK-2B package is easy to use thanks to the PressFit pins and the exposed substrate provides improved thermal performance. The optimized layout also helps to minimize stray parameters, allowing for better EMI performance.

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
Operating junction temperature	T_J		175	°C
Storage temperature range	T_{Stg}		-40 to +150	
RMS isolation voltage	V_{ISOL}	$T_J = 25$ °C, all terminals shorted, $f = 50$ Hz, $t = 1$ s	3500	V
Q1 - Q4 IGBT				
Collector to emitter voltage	V_{CES}		600	V
Gate to emitter voltage	V_{GES}		20	
Pulsed collector current	I_{CM}		200	A
Clamped inductive load current	$I_{LM}^{(1)}$		200	
Continuous collector current	I_C	$T_C = 25$ °C	109	A
		$T_C = 80$ °C	80	
		$T_{SINK} = 80$ °C	40	
Power dissipation	P_D	$T_C = 25$ °C	294	W
		$T_C = 80$ °C	186	
Q2 - Q3 IGBT				
Collector to emitter voltage	V_{CES}		600	V
Gate to emitter voltage	V_{GES}		20	
Pulsed collector current	I_{CM}		250	A
Clamped inductive load current	$I_{LM}^{(1)}$		250	
Continuous collector current	I_C	$T_C = 25$ °C	154	A
		$T_C = 80$ °C	113	
		$T_{SINK} = 80$ °C	50	
Power dissipation	P_D	$T_C = 25$ °C	405	W
		$T_C = 80$ °C	257	



ABSOLUTE MAXIMUM RATINGS				
D5 - D6 CLAMPING DIODE				
Repetitive peak reverse voltage	V_{RRM}		600	V
Single pulse forward current	I_{FSM}	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	270	A
Diode continuous forward current	I_F	$T_C = 25\text{ }^\circ\text{C}$	78	
		$T_C = 80\text{ }^\circ\text{C}$	55	
		$T_{SINK} = 80\text{ }^\circ\text{C}$	28	
Power dissipation	P_D	$T_C = 25\text{ }^\circ\text{C}$	174	W
		$T_C = 80\text{ }^\circ\text{C}$	110	
D1 - D2 - D3 - D4 AP DIODE				
Single pulse forward current	I_{FSM}	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	250	A
Diode continuous forward current	I_F	$T_C = 25\text{ }^\circ\text{C}$	72	
		$T_C = 80\text{ }^\circ\text{C}$	70	
		$T_{SINK} = 80\text{ }^\circ\text{C}$	31	
Power dissipation	P_D	$T_C = 25\text{ }^\circ\text{C}$	107	W
		$T_C = 80\text{ }^\circ\text{C}$	68	

Notes

- Absolute Maximum Ratings indicate sustained limits beyond which damage to the device may occur.
- (1) $V_{CC} = 300\text{ V}$, $V_{GE} = 15\text{ V}$, $L = 500\text{ }\mu\text{H}$, $R_g = 4.7\text{ }\Omega$, $T_J = 175\text{ }^\circ\text{C}$

ELECTRICAL SPECIFICATIONS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Q1 - Q4 IGBT						
Collector to emitter breakdown voltage	BV_{CES}	$V_{GE} = 0\text{ V}$, $I_C = 100\text{ }\mu\text{A}$	600	-	-	V
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}$, $I_C = 60\text{ A}$	-	1.57	1.8	V
		$V_{GE} = 15\text{ V}$, $I_C = 75\text{ A}$	-	1.7	1.93	
		$V_{GE} = 15\text{ V}$, $I_C = 60\text{ A}$, $T_J = 125\text{ }^\circ\text{C}$	-	1.7	-	
		$V_{GE} = 15\text{ V}$, $I_C = 75\text{ A}$, $T_J = 125\text{ }^\circ\text{C}$	-	1.86	-	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$, $I_C = 2.1\text{ mA}$	3.6	5.6	7.1	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}$, $I_C = 1\text{ mA}$ ($25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$)	-	-12	-	mV/ $^\circ\text{C}$
Forward transconductance	g_{fe}	$V_{CE} = 20\text{ V}$, $I_C = 75\text{ A}$	-	51	-	S
Transfer characteristics	V_{GE}	$V_{CE} = 20\text{ V}$, $I_C = 75\text{ A}$	-	9.6	-	V
Zero gate voltage collector current	I_{CES}	$V_{GE} = 0\text{ V}$, $V_{CE} = 600\text{ V}$	-	0.0002	0.1	mA
		$V_{GE} = 0\text{ V}$, $V_{CE} = 600\text{ V}$, $T_J = 125\text{ }^\circ\text{C}$	-	0.01	-	
Gate to emitter leakage current	I_{GES}	$V_{GE} = \pm 20\text{ V}$, $V_{CE} = 0\text{ V}$	-	-	± 200	nA



ELECTRICAL SPECIFICATIONS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Q2 - Q3 IGBT						
Collector to emitter breakdown voltage	BV_{CES}	$V_{GE} = 0\text{ V}, I_C = 500\text{ }\mu\text{A}$	600	-	-	V
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}, I_C = 60\text{ A}$	-	1.45	1.62	V
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}$	-	1.56	1.73	
		$V_{GE} = 15\text{ V}, I_C = 60\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.52	-	
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.67	-	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}, I_C = 5.6\text{ mA}$	3.6	5.3	7.1	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}, I_C = 1.4\text{ mA}$ (25 °C to 125 °C)	-	-18	-	mV/°C
Forward transconductance	g_{fe}	$V_{CE} = 20\text{ V}, I_C = 75\text{ A}$	-	72	-	S
Transfer characteristics	V_{GE}	$V_{CE} = 20\text{ V}, I_C = 75\text{ A}$	-	8.3	-	V
Zero gate voltage collector current	I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 600\text{ V}$	-	0.0005	0.1	mA
		$V_{GE} = 0\text{ V}, V_{CE} = 600\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	0.065	-	
Gate to emitter leakage current	I_{GES}	$V_{GE} = \pm 20\text{ V}, V_{CE} = 0\text{ V}$	-	-	± 400	nA
D5 - D6 CLAMPING DIODE						
Cathode to anode blocking voltage	V_{BR}	$I_R = 100\text{ }\mu\text{A}$	600	-	-	V
Forward voltage drop	V_{FM}	$I_F = 40\text{ A}$	-	1.83	2.35	
		$I_F = 40\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.51	-	
Reverse leakage current	I_{RM}	$V_R = 600\text{ V}$	-	0.0002	0.1	mA
		$V_R = 600\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	0.028	-	
D1 - D2 - D3 - D4 AP DIODE						
Forward voltage drop	V_{FM}	$I_F = 30\text{ A}$	-	1.2	1.41	V
		$I_F = 30\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.06	-	



SWITCHING CHARACTERISTICS ($T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Q1 - Q4 IGBT (WITH D5 - D6 CLAMPING DIODE)						
Total gate charge (turn-on)	Q_g	$I_C = 75\text{ A}$	-	150	-	nC
Gate to emitter charge (turn-on)	Q_{ge}	$V_{CC} = 400\text{ V}$	-	40	-	
Gate to collector charge (turn-on)	Q_{gc}	$V_{GE} = 15\text{ V}$	-	60	-	
Turn-on switching loss	E_{ON}	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.94	-	mJ
Turn-off switching loss	E_{OFF}		-	1.1	-	
Total switching loss	E_{TOT}		-	2.04	-	
Turn-on delay time	$t_{d(on)}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	78	-	ns
Rise time	t_r		-	72	-	
Turn-off delay time	$t_{d(off)}$		-	101	-	
Fall time	t_f		-	65	-	
Turn-on switching loss	E_{ON}		-	1.13	-	
Turn-off switching loss	E_{OFF}	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	1.61	-	mJ
Total switching loss	E_{TOT}		-	2.74	-	
Turn-on delay time	$t_{d(on)}$		-	78	-	
Rise time	t_r	$V_{GE} = 0\text{ V}$ $V_{CC} = 30\text{ V}$ $f = 1\text{ MHz}$	-	72	-	ns
Turn-off delay time	$t_{d(off)}$		-	106	-	
Fall time	t_f		-	107	-	
Input capacitance	C_{ies}		-	4440	-	
Output capacitance	C_{oes}		-	245	-	
Reverse transfer capacitance	C_{res}	-	130	-	pF	
Reverse bias safe operating area	RBSOA	$T_J = 175\text{ }^\circ\text{C}$, $I_C = 200\text{ A}$ $V_{CC} = 300\text{ V}$, $V_P = 600\text{ V}$ $R_g = 4.7\text{ }\Omega$, $V_{GE} = 15\text{ V to }0\text{ V}$	Fullsquare			
Short circuit safe operating area	SCSOA	$R_g = 10\text{ }\Omega$, $V_{CC} = 400\text{ V}$, $V_P = 600\text{ V}$ $V_{GE} = 15\text{ V to }0$	-	-	5	μs
Q2 - Q3 IGBT (WITH FREEWHEELING EXTERNAL TO-247 DIODE DISCRETE 30ETH06)						
Total gate charge (turn-on)	Q_g	$I_C = 120\text{ A}$	-	240	-	nC
Gate to emitter charge (turn-on)	Q_{ge}	$V_{CC} = 400\text{ V}$	-	69	-	
Gate to collector charge (turn-on)	Q_{gc}	$V_{GE} = 15\text{ V}$	-	90	-	
Turn-on switching loss	E_{ON}	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.85	-	mJ
Turn-off switching loss	E_{OFF}		-	1.54	-	
Total switching loss	E_{TOT}		-	2.39	-	
Turn-on delay time	$t_{d(on)}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	111	-	ns
Rise time	t_r		-	81	-	
Turn-off delay time	$t_{d(off)}$		-	130	-	
Fall time	t_f		-	74	-	
Turn-on switching loss	E_{ON}		-	1.0	-	
Turn-off switching loss	E_{OFF}	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	1.83	-	mJ
Total switching loss	E_{TOT}		-	2.83	-	
Turn-on delay time	$t_{d(on)}$		-	111	-	
Rise time	t_r	$V_{GE} = 0\text{ V}$ $V_{CC} = 30\text{ V}$ $f = 1\text{ MHz}$	-	83	-	ns
Turn-off delay time	$t_{d(off)}$		-	140	-	
Fall time	t_f		-	104	-	
Input capacitance	C_{ies}		-	7750	-	
Output capacitance	C_{oes}		-	550	-	
Reverse transfer capacitance	C_{res}	-	225	-	pF	
Reverse bias safe operating area	RBSOA	$T_J = 175\text{ }^\circ\text{C}$, $I_C = 250\text{ A}$ $V_{CC} = 300\text{ V}$, $V_P = 600\text{ V}$ $R_g = 4.7\text{ }\Omega$, $V_{GE} = 15\text{ V to }0\text{ V}$	Fullsquare			
Short circuit safe operating area	SCSOA	$R_g = 10\text{ }\Omega$, $V_{CC} = 400\text{ V}$, $V_P = 600\text{ V}$ $V_{GE} = 15\text{ V to }0$	-	-	5	μs



SWITCHING CHARACTERISTICS (T _J = 25 °C unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
D5 - D6 CLAMPING DIODE						
Diode reverse recovery time	t _{rr}	V _R = 200 V	-	59	-	ns
Diode peak reverse current	I _{rr}	I _F = 50 A	-	8.5	-	A
Diode recovery charge	Q _{rr}	di/dt = 500 A/μs	-	257	-	nC
Diode reverse recovery time	t _{rr}	V _R = 200 V	-	110	-	ns
Diode peak reverse current	I _{rr}	I _F = 50 A	-	18.5	-	A
Diode recovery charge	Q _{rr}	di/dt = 500 A/μs, T _J = 125 °C	-	1020	-	nC
D1 - D2 - D3 - D4 AP DIODE						
Diode reverse recovery time	t _{rr}	V _R = 200 V	-	108	-	ns
Diode peak reverse current	I _{rr}	I _F = 50 A	-	19.5	-	A
Diode recovery charge	Q _{rr}	di/dt = 500 A/μs	-	1062	-	nC
Diode reverse recovery time	t _{rr}	V _R = 200 V	-	174	-	ns
Diode peak reverse current	I _{rr}	I _F = 50 A	-	31	-	A
Diode recovery charge	Q _{rr}	di/dt = 500 A/μs, T _J = 125 °C	-	2716	-	nC

Note

(1) Energy losses include "tail" and diode reverse recovery.

INTERNAL NTC - THERMISTOR SPECIFICATIONS				
PARAMETER	SYMBOL	TEST CONDITIONS	TYP.	UNITS
Resistance	R ₂₅	T _J = 25 °C	5000 ± 5 %	Ω
	R ₁₂₅	T _J = 125 °C	493 ± 5 %	
B-constant	B	R ₂ = R ₁ e ^[B(1/T₂ - 1/T₁)]	3375 ± 5 %	K
Temperature range			-40 to 125	°C
Maximum operating temperature			220	
Dissipation constant			2	mW/°C
Thermal time constant			8	s

THERMAL AND MECHANICAL SPECIFICATIONS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS
Q1 - Q4 IGBT - Junction to case thermal resistance (per switch)	R _{thJC}	-	-	0.51	°C/W
Q2 - Q3 IGBT - Junction to case thermal resistance (per switch)		-	-	0.37	
D5 - D6 Clamping diode - Junction to case thermal resistance (per diode)		-	-	0.86	
D1 - D2 - D3 - D4 AP diode - Junction to case thermal resistance (per diode)		-	-	1.4	
Q1 - Q4 IGBT - Case to sink thermal resistance (per switch)	R _{thCS} ⁽¹⁾	-	0.84	-	
Q2 - Q3 IGBT - Case to sink thermal resistance (per switch)		-	0.8	-	
D5 - D6 Clamping diode - Case to sink thermal resistance (per diode)		-	1.16	-	
D1 - D2 - D3 - D4 AP diode - Case to sink thermal resistance (per diode)		-	1.12	-	
Case to sink thermal resistance per module		-	0.1	-	°C/W
Mounting torque (M4)		2	-	3	Nm
Weight		-	45	-	g

Note

(1) Mounting surface flat, smooth, and greased

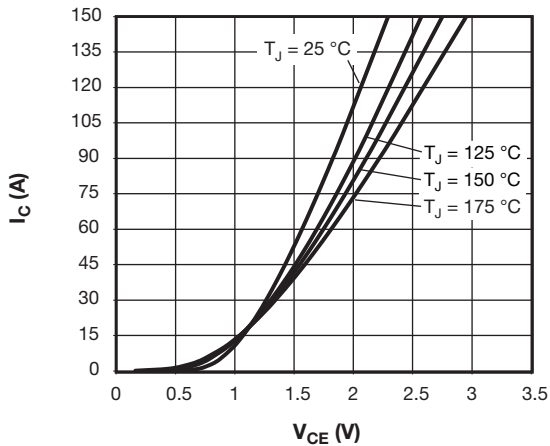


Fig. 1 - Typical Q1 - Q4 Trench IGBT Output Characteristics
 $V_{GE} = 15\text{ V}$

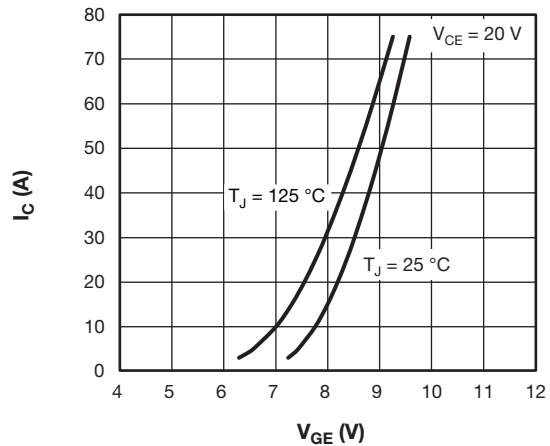


Fig. 4 - Typical Q1 - Q4 Trench IGBT Transfer Characteristics

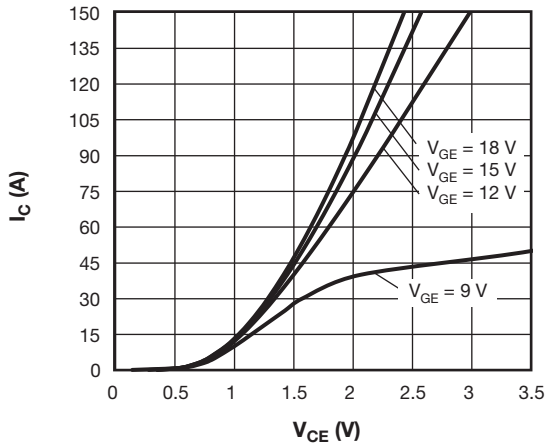


Fig. 2 - Typical Q1 - Q4 Trench IGBT Output Characteristics
 $T_J = 125\text{ °C}$

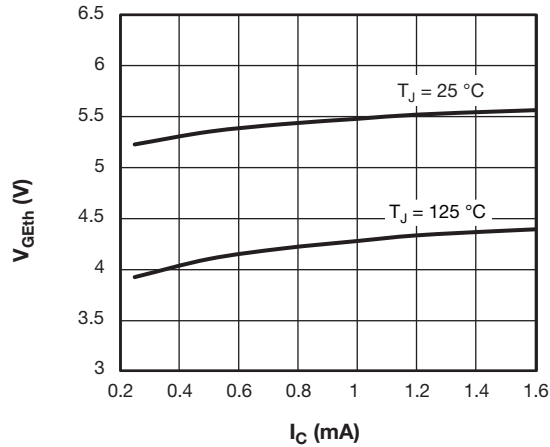


Fig. 5 - Typical Q1 - Q4 Trench IGBT Gate Threshold Voltage

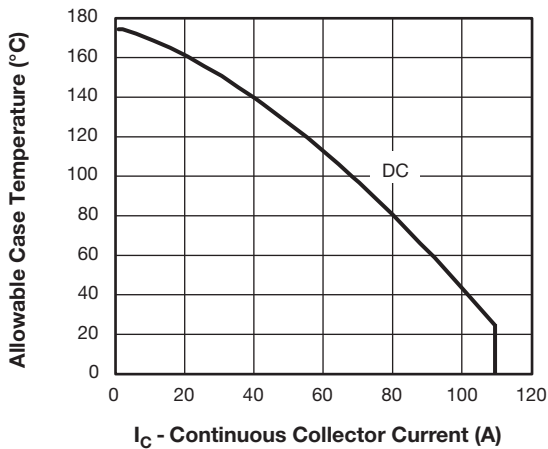


Fig. 3 - Maximum Q1 - Q4 Trench IGBT Continuous Collector Current vs. Case Temperature

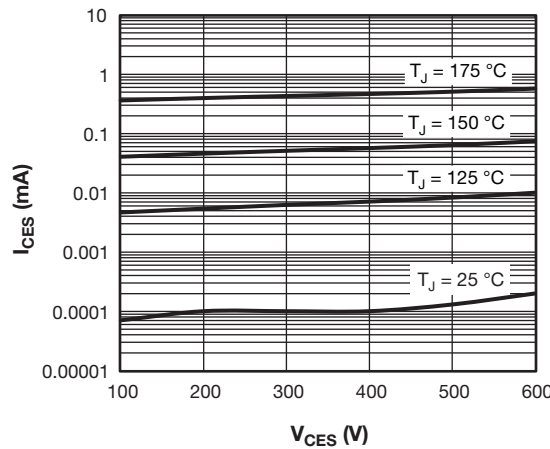


Fig. 6 - Typical Q1 - Q4 Trench IGBT Zero Gate Voltage Collector Current

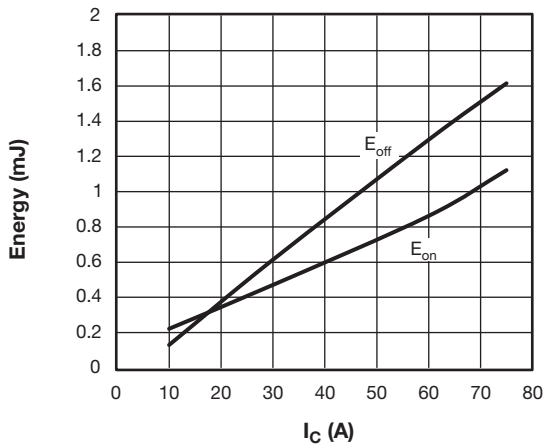


Fig. 7 - Typical Q1 - Q4 Trench IGBT Energy Loss vs. I_C (with D5 - D6 Clamping Diode)
 $T_J = 125^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $R_g = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

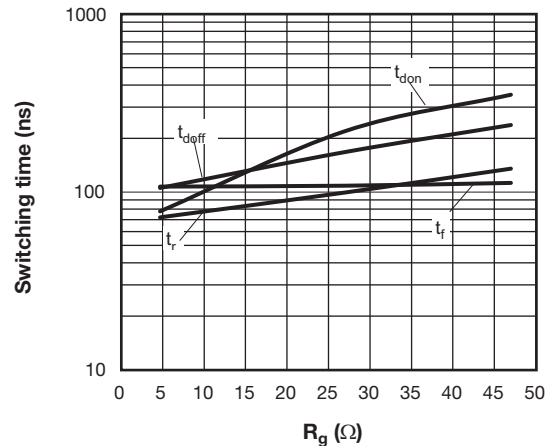


Fig. 10 - Typical Q1 - Q4 Trench IGBT Switching Time vs. R_g (with D5 - D6 Clamping Diode)
 $T_J = 125^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $I_C = 75\text{ A}$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

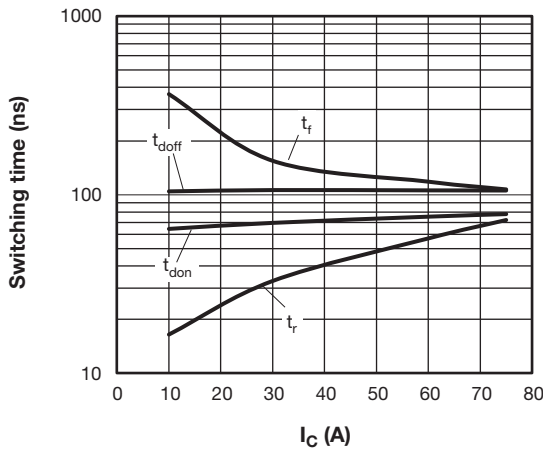


Fig. 8 - Typical Q1 - Q4 Trench IGBT Switching Loss vs. I_C (with D5 - D6 Clamping Diode)
 $T_J = 125^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $R_g = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

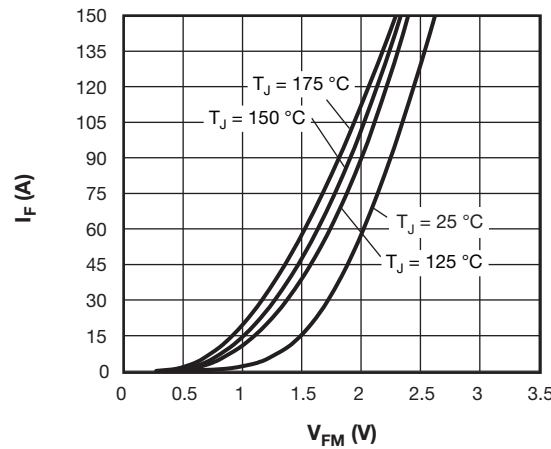


Fig. 11 - Typical D5 - D6 Clamping Diode Forward Characteristics

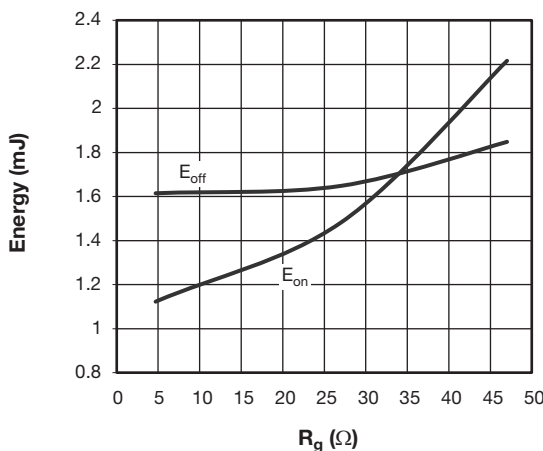


Fig. 9 - Typical Q1 - Q4 Trench IGBT Energy Loss vs. R_g (with D5 - D6 Clamping Diode)
 $T_J = 125^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $I_C = 75\text{ A}$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

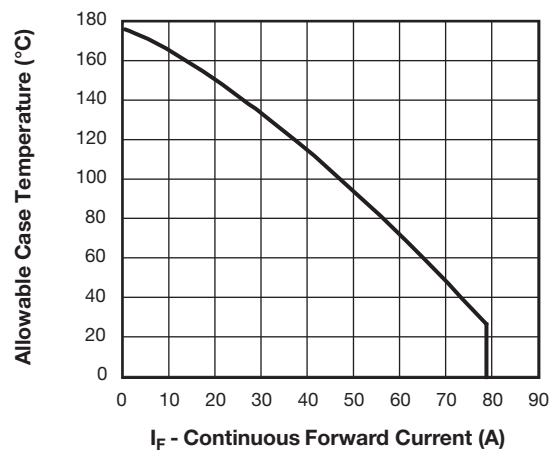


Fig. 12 - Maximum D5 - D6 Clamping Diode Forward Current vs. Case Temperature

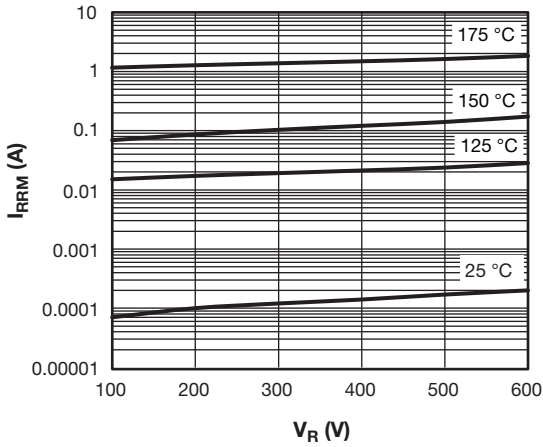


Fig. 13 - Typical D5 - D6 Clamping Diode Reverse Leakage Current

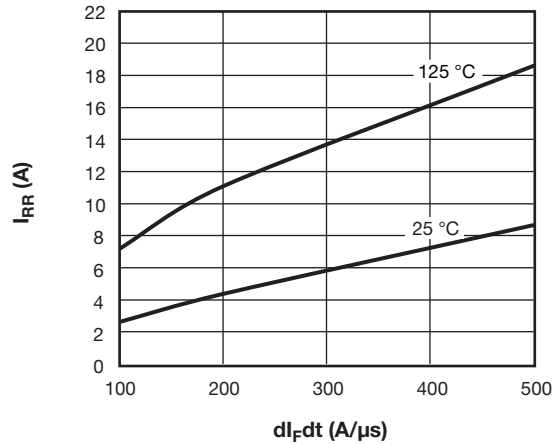


Fig. 15 - Typical D5 - D6 Clamping Diode Reverse Recovery Current vs. di_F/dt , $V_{Rr} = 200\text{ V}$, $I_F = 50\text{ A}$

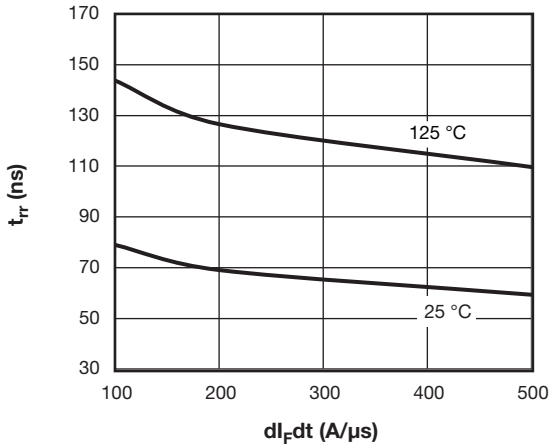


Fig. 14 - Typical D5 - D6 Clamping Diode Reverse Recovery Time vs. di_F/dt , $V_{Rr} = 200\text{ V}$, $I_F = 50\text{ A}$

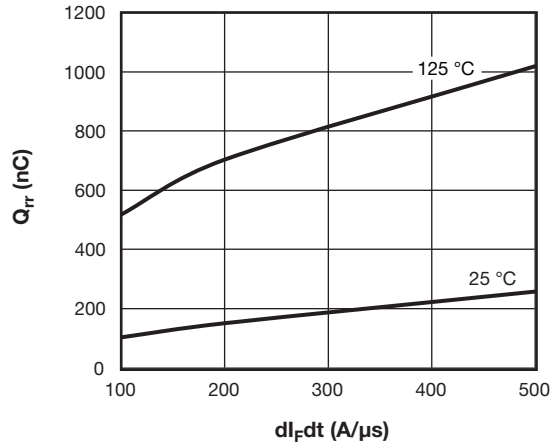


Fig. 16 - Typical D5 - D6 Clamping Diode Reverse Recovery Charge vs. di_F/dt , $V_{Rr} = 200\text{ V}$, $I_F = 50\text{ A}$

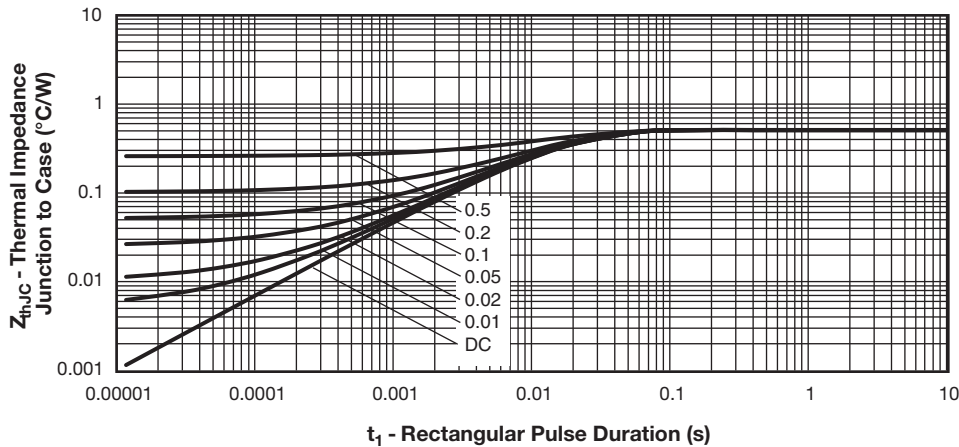


Fig. 17 - Maximum Thermal Impedance Z_{thJc} Characteristics (Q1 - Q4 Trench IGBT)

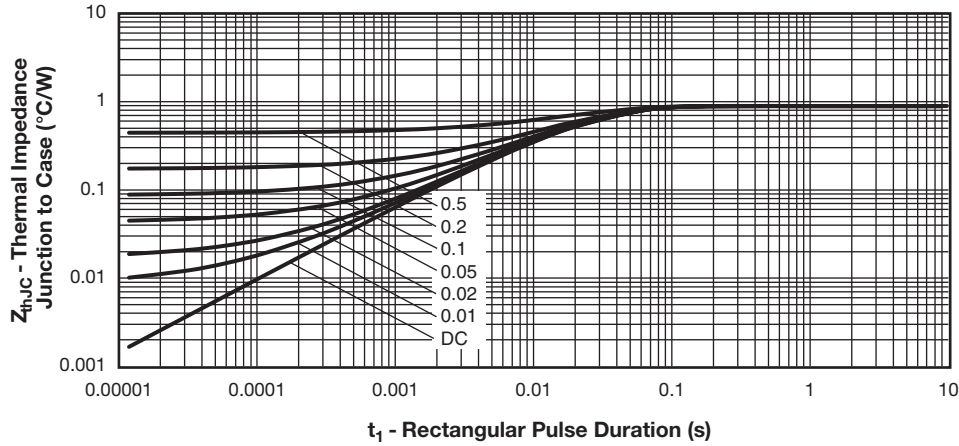


Fig. 18 - Maximum Thermal Impedance Z_{thJC} Characteristics (D5 - D6 Clamping Diode)

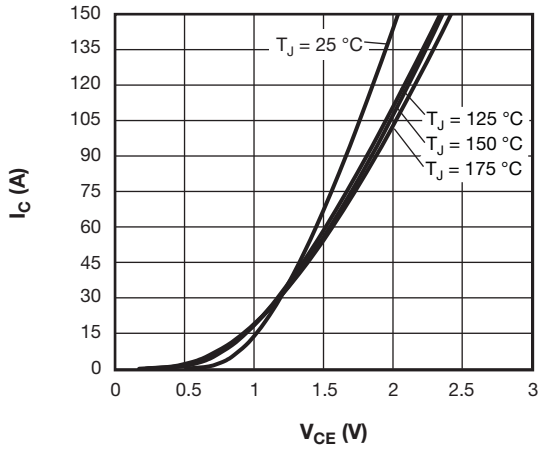


Fig. 19 - Typical Q2 - Q3 Trench IGBT Output Characteristics
 $V_{GE} = 15\text{ V}$

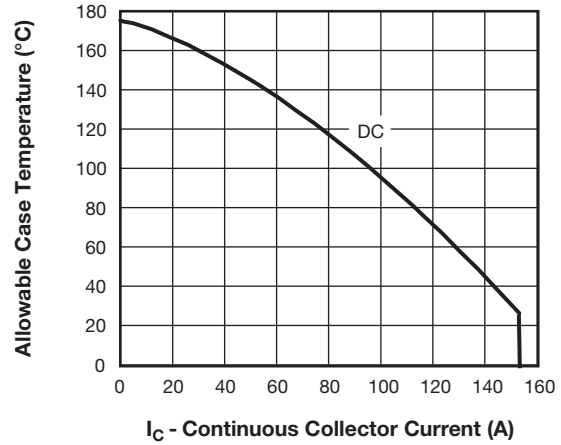


Fig. 21 - Maximum Q2 - Q3 Trench IGBT Continuous Collector Current vs. Case Temperature

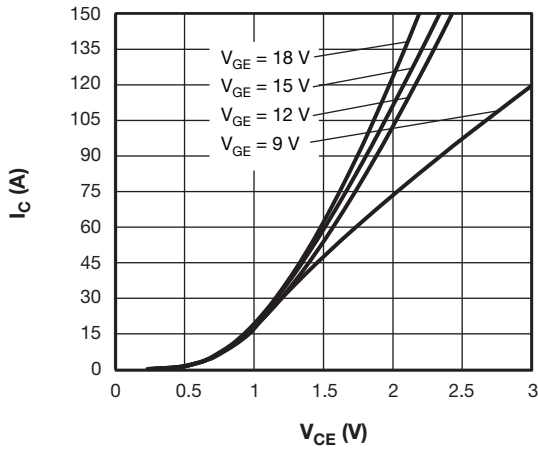


Fig. 20 - Typical Q2 - Q3 Trench IGBT Output Characteristics
 $T_J = 125\text{ °C}$

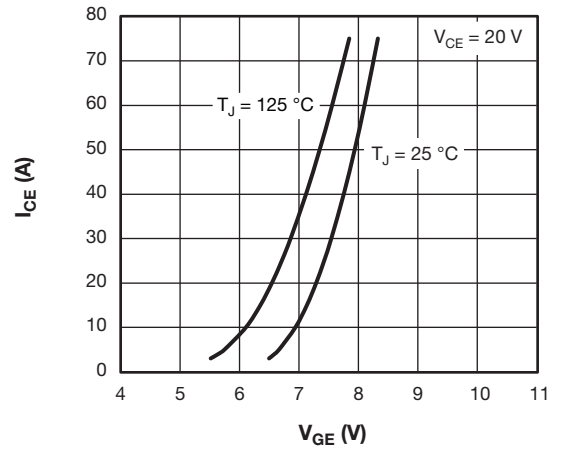


Fig. 22 - Typical Q2 - Q3 Trench IGBT Transfer Characteristics

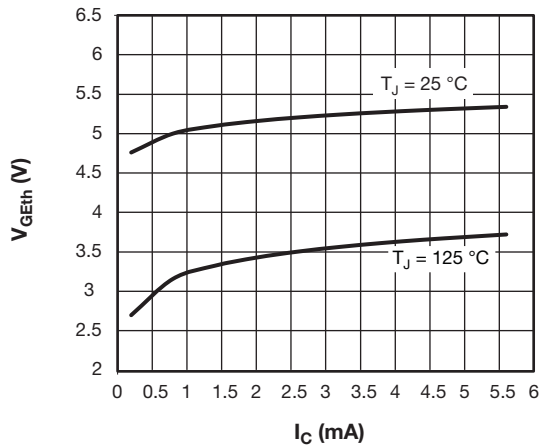


Fig. 23 - Typical Q2 - Q3 Trench IGBT Gate Threshold Voltage

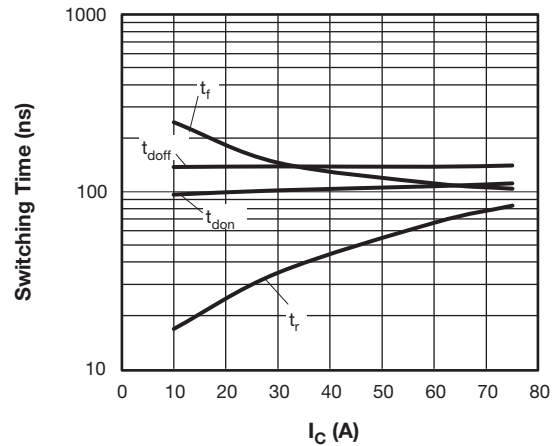


Fig. 26 - Typical Q2 - Q3 Trench IGBT Switching Time vs. I_C (with Freewheeling External TO-247 Diode Discrete 30ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $R_g = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

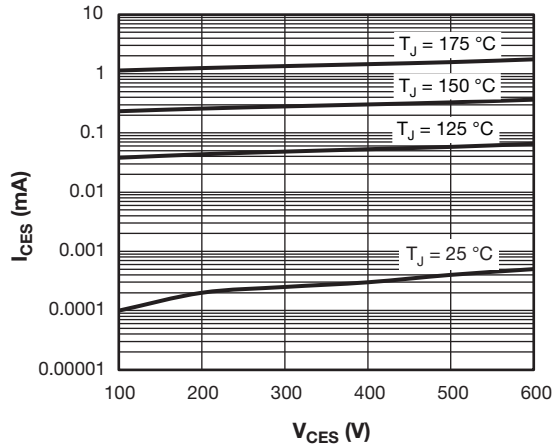


Fig. 24 - Typical Q2 - Q3 Trench IGBT Zero Gate Voltage Collector Current

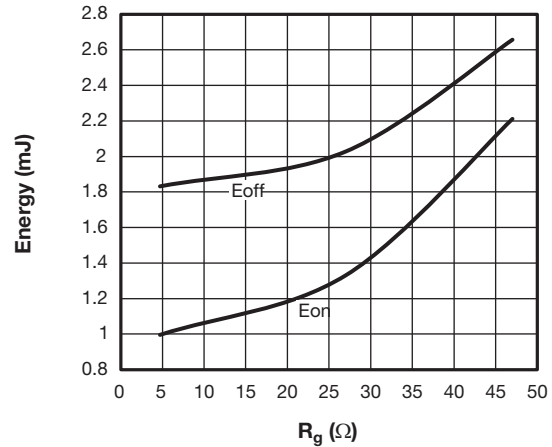


Fig. 27 - Typical Q2 - Q3 Trench IGBT Energy Loss vs. R_g (with Freewheeling External TO-247 Diode Discrete 30ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $I_C = 75\text{ A}$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

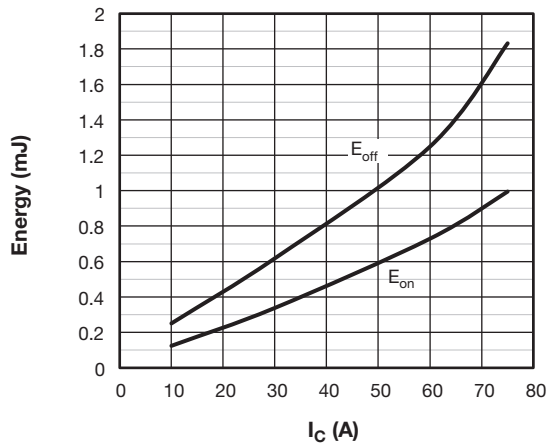


Fig. 25 - Typical Q2 - Q3 Trench IGBT Energy Loss vs. I_C (with Freewheeling External TO-247 Diode Discrete 30ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $R_g = 4.7\ \Omega$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

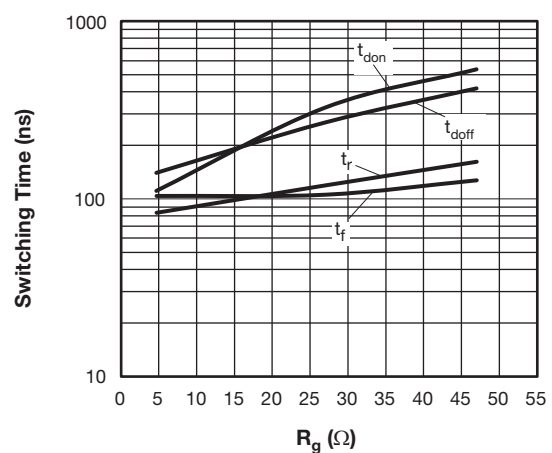


Fig. 28 - Typical Q2 - Q3 Trench IGBT Switching Time vs. R_g (with Freewheeling External TO-247 Diode Discrete 30ETH06), $T_J = 125\text{ }^\circ\text{C}$, $V_{CC} = 300\text{ V}$, $I_C = 75\text{ A}$, $V_{GE} = 15\text{ V}$, $L = 500\ \mu\text{H}$

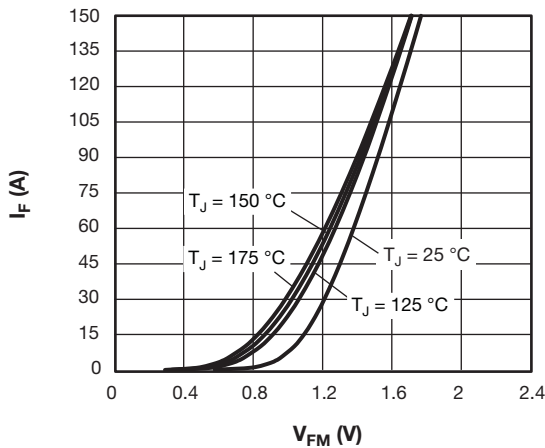


Fig. 29 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Forward Characteristics

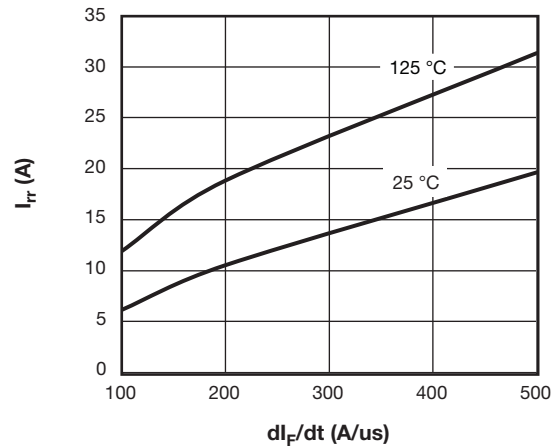


Fig. 32 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Current vs. di_F/dt
 $V_{rr} = 200\text{ V}$, $I_F = 50\text{ A}$

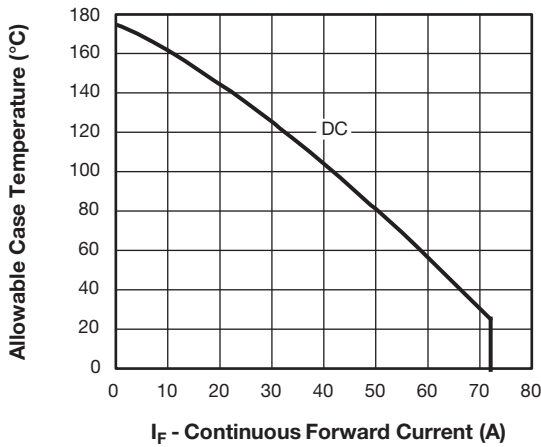


Fig. 30 - Maximum D1 - D2 - D3 - D4 Antiparallel Diode Forward Current vs. Case Temperature

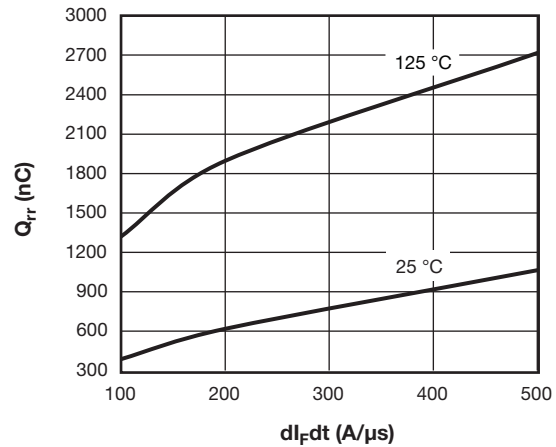


Fig. 33 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Charge vs. di_F/dt
 $V_{rr} = 200\text{ V}$, $I_F = 50\text{ A}$

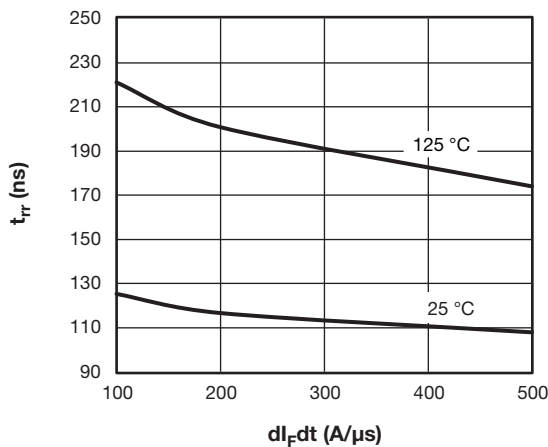


Fig. 31 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Time vs. di_F/dt
 $V_{rr} = 200\text{ V}$, $I_F = 50\text{ A}$

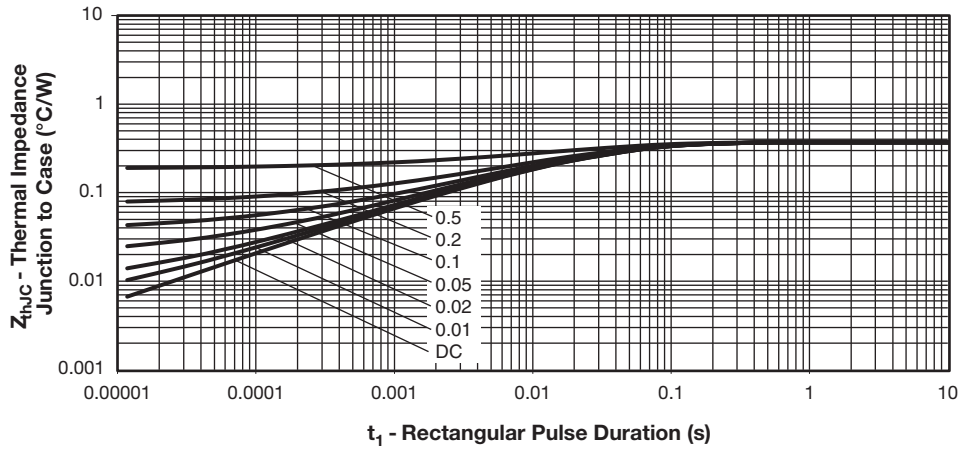


Fig. 34 - Maximum Thermal Impedance Z_{thJC} Characteristics (Q2 - Q3 Trench IGBT)

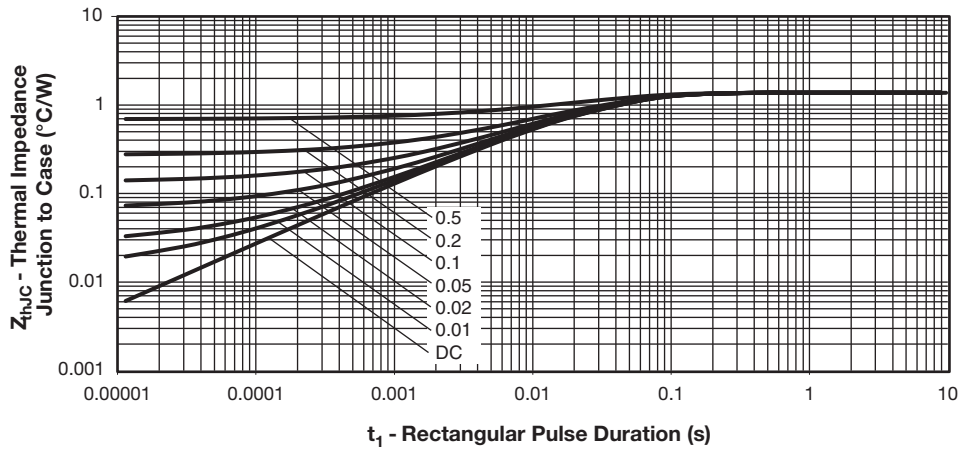


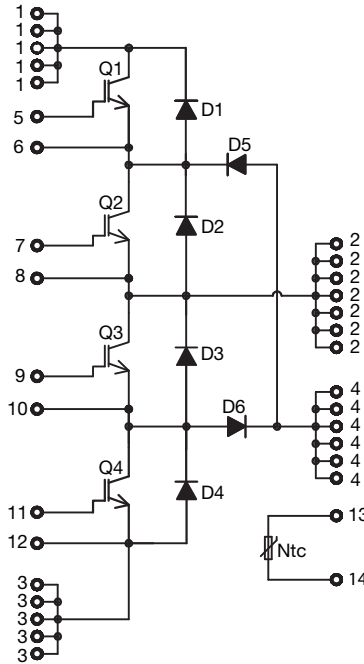
Fig. 35 - Maximum Thermal Impedance Z_{thJC} Characteristics (D1 - D2 - D3 - D4 Antiparallel Diode)

ORDERING INFORMATION TABLE

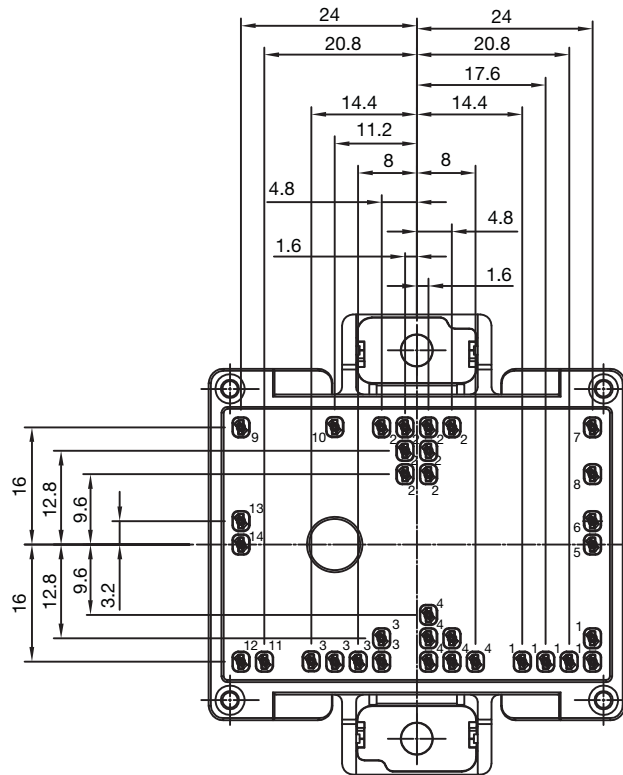
Device code	VS-	ET	F	075	Y	60	U
	①	②	③	④	⑤	⑥	⑦

- 1** - Vishay Semiconductors product
- 2** - Package indicator (ET = EMIPAK-2B)
- 3** - Circuit configuration (F = 3-levels half-bridge inverter stage)
- 4** - Current rating (075 = 75 A)
- 5** - Switch die technology (Y = Trench IGBT)
- 6** - Voltage rating (60 = 600 V)
- 7** - Diode die technology (U = Ultrafast diode)

CIRCUIT CONFIGURATION



PACKAGE

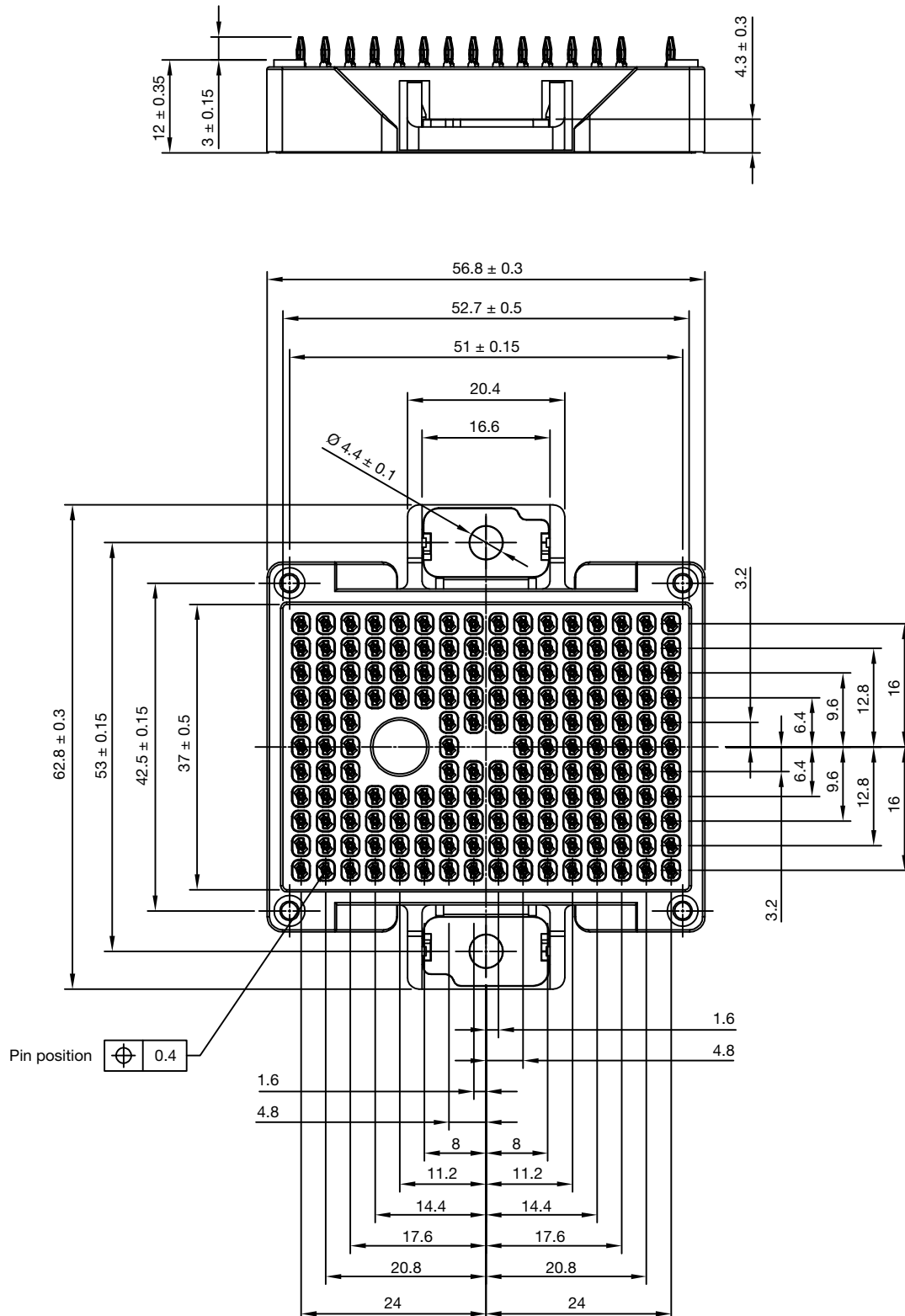


LINKS TO RELATED DOCUMENTS	
Dimensions	www.vishay.com/doc?95559



EMIPAK-2B PressFit

DIMENSIONS in millimeters





Disclaimer

ALL PRODUCT, PRODUCT SPECIFICATIONS AND DATA ARE SUBJECT TO CHANGE WITHOUT NOTICE TO IMPROVE RELIABILITY, FUNCTION OR DESIGN OR OTHERWISE.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained in any datasheet or in any other disclosure relating to any product.

Vishay makes no warranty, representation or guarantee regarding the suitability of the products for any particular purpose or the continuing production of any product. To the maximum extent permitted by applicable law, Vishay disclaims (i) any and all liability arising out of the application or use of any product, (ii) any and all liability, including without limitation special, consequential or incidental damages, and (iii) any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.

Statements regarding the suitability of products for certain types of applications are based on Vishay's knowledge of typical requirements that are often placed on Vishay products in generic applications. Such statements are not binding statements about the suitability of products for a particular application. It is the customer's responsibility to validate that a particular product with the properties described in the product specification is suitable for use in a particular application. Parameters provided in datasheets and/or specifications may vary in different applications and performance may vary over time. All operating parameters, including typical parameters, must be validated for each customer application by the customer's technical experts. Product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein.

Except as expressly indicated in writing, Vishay products are not designed for use in medical, life-saving, or life-sustaining applications or for any other application in which the failure of the Vishay product could result in personal injury or death. Customers using or selling Vishay products not expressly indicated for use in such applications do so at their own risk. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay. Product names and markings noted herein may be trademarks of their respective owners.

Material Category Policy

Vishay Intertechnology, Inc. hereby certifies that all its products that are identified as RoHS-Compliant fulfill the definitions and restrictions defined under Directive 2011/65/EU of The European Parliament and of the Council of June 8, 2011 on the restriction of the use of certain hazardous substances in electrical and electronic equipment (EEE) - recast, unless otherwise specified as non-compliant.

Please note that some Vishay documentation may still make reference to RoHS Directive 2002/95/EC. We confirm that all the products identified as being compliant to Directive 2002/95/EC conform to Directive 2011/65/EU.

Vishay Intertechnology, Inc. hereby certifies that all its products that are identified as Halogen-Free follow Halogen-Free requirements as per JEDEC JS709A standards. Please note that some Vishay documentation may still make reference to the IEC 61249-2-21 definition. We confirm that all the products identified as being compliant to IEC 61249-2-21 conform to JEDEC JS709A standards.

Данный компонент на территории Российской Федерации

Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

Офис по работе с юридическими лицами:

105318, г.Москва, ул.Щербаковская д.3, офис 1107, 1118, ДЦ «Щербаковский»

Телефон: +7 495 668-12-70 (многоканальный)

Факс: +7 495 668-12-70 (доб.304)

E-mail: info@moschip.ru

Skype отдела продаж:

moschip.ru

moschip.ru_4

moschip.ru_6

moschip.ru_9